

# Ar experiments and analysis

Francisco Guzmán

ADAS-EU  
University of Strathclyde

ADAS-EU course – 26 – 30 Mars 2012

- 1 Motivation
- 2 CXRS analysis tools
- 3 CXRS experiments on Boron and Neon
- 4 Ar experiments

- 1 Motivation
- 2 CXRS analysis tools
- 3 CXRS experiments on Boron and Neon
- 4 Ar experiments

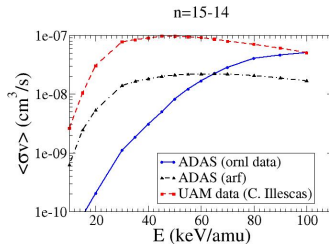
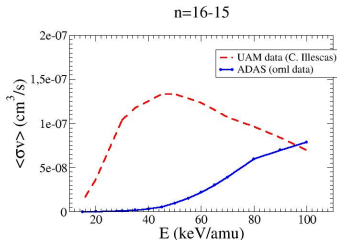
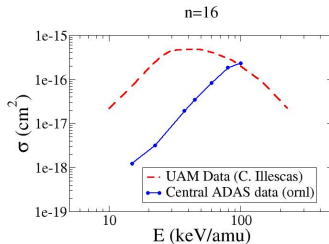
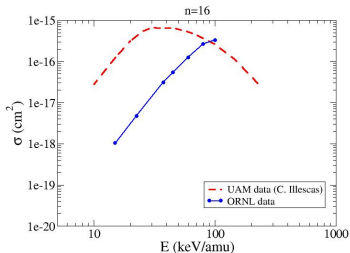
- 1 Motivation
- 2 CXRS analysis tools
- 3 CXRS experiments on Boron and Neon
- 4 Ar experiments

- 1 Motivation
- 2 CXRS analysis tools
- 3 CXRS experiments on Boron and Neon
- 4 Ar experiments

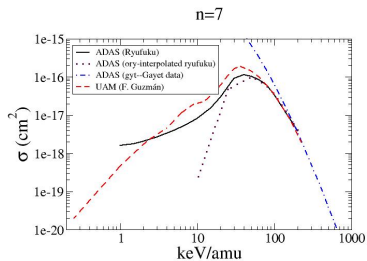
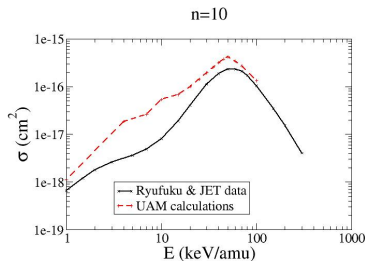
# Outline

- 1 Motivation
- 2 CXRS analysis tools
- 3 CXRS experiments on Boron and Neon
- 4 Ar experiments

# ADAS sets comparison

 $\text{Ar}^{16+} + \text{H}$ 


## not only Ar!



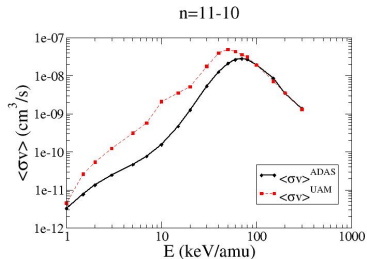
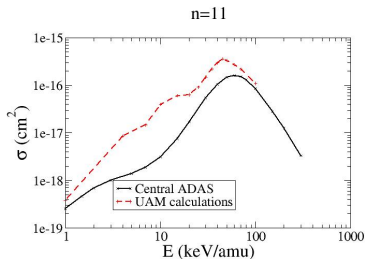
UAM: Errea *et al.* Nucl Inst. & Meth. Phys. Res. B **235**, 315 (2005)

ADAS: Ryufuku JAERI-M-82-03 and JET data base (Summers and Horton) ( $n > 10$  extrapolated)



## Differences on Ne

Differences in cross section are reflected in effective coefficients



Plasma Parameters:

$$\begin{aligned}
 n_i &= 4 \cdot 10^{13} \text{ cm}^{-3} \\
 T_i &= 3 \text{ keV} \\
 Z_{\text{eff}} &= 1.7 \\
 B &= 3 \text{ T}
 \end{aligned}$$

# Outline

- 1 Motivation
- 2 CXRS analysis tools**
- 3 CXRS experiments on Boron and Neon
- 4 Ar experiments

# Using CHEAP

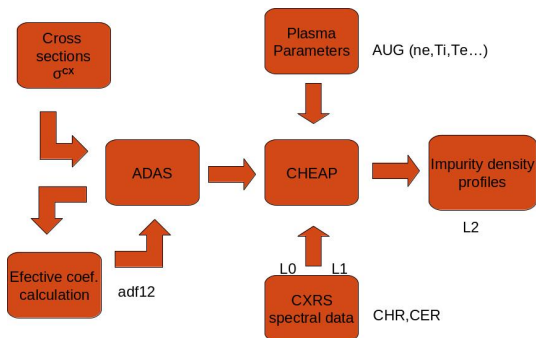
- CHarge Exchange Analysis Package (CHEAP) calculates iteratively impurity and beam density in plasmas from a spectral line photon **flux** and **effective rates**.

$$n_z = \frac{\phi_{CX}^z}{q_{eff}^{CX} n_{beam}}$$

- Flux will be fitted using CXFIT.
- CHEAP has been developed by M. von Hellerman and others in JET.

# Using CHEAP

- CHarge Exchange Analysis Package (CHEAP) calculates iteratively impurity and beam density in plasmas from a spectral line photon **flux** and **effective rates**.



# What does CHEAP do?

- $(T_i, T_e, n_e, \phi_{CX})$  profiles  $\implies$  beam density attenuation  $\implies$  calculated photon flux  $\implies$  impurity densities.
- CHEAP can use several background impurities to calculate beam attenuation.
- $q_{eff}(Z, H(n = 1, 2))$  CX data is used to calculate beam attenuation.
- $Z_{eff}^{CX}$  could be calculated from impurity profiles and can be implemented.

# What does CHEAP do?

- $(T_i, T_e, n_e, \phi_{CX})$  profiles  $\implies$  beam density attenuation  $\implies$  calculated photon flux  $\implies$  impurity densities.
- CHEAP can use several background impurities to calculate beam attenuation.
- $q_{eff}(Z, H(n = 1, 2))$  CX data is used to calculate beam attenuation.
- $Z_{eff}^{CX}$  could be calculated from impurity profiles and can be implemented.

# What does CHEAP do?

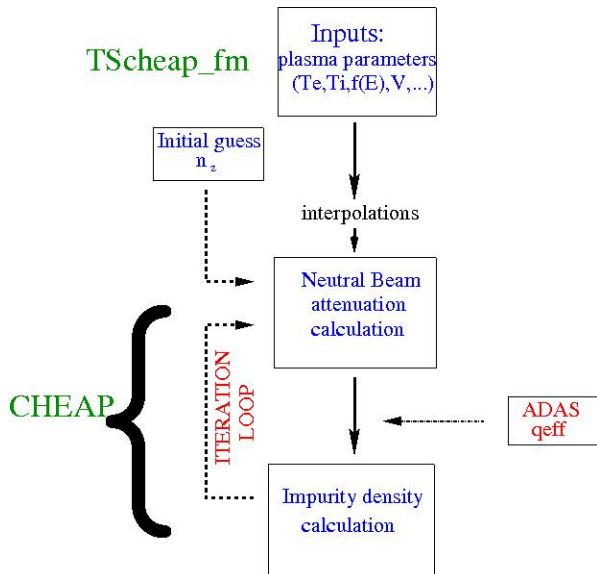
- $(T_i, T_e, n_e, \phi_{CX})$  profiles  $\implies$  beam density attenuation  $\implies$  calculated photon flux  $\implies$  impurity densities.
- CHEAP can use several background impurities to calculate beam attenuation.
- $q_{eff}(Z, H(n = 1, 2))$  CX data is used to calculate beam attenuation.
- $Z_{eff}^{CX}$  could be calculated from impurity profiles and can be implemented.

# What does CHEAP do?

- $(T_i, T_e, n_e, \phi_{CX})$  profiles  $\implies$  beam density attenuation  $\implies$  calculated photon flux  $\implies$  impurity densities.
- CHEAP can use several background impurities to calculate beam attenuation.
- $q_{eff}(Z, H(n = 1, 2))$  CX data is used to calculate beam attenuation.
- $Z_{eff}^{CX}$  could be calculated from impurity profiles and can be implemented.



## CHEAP structure

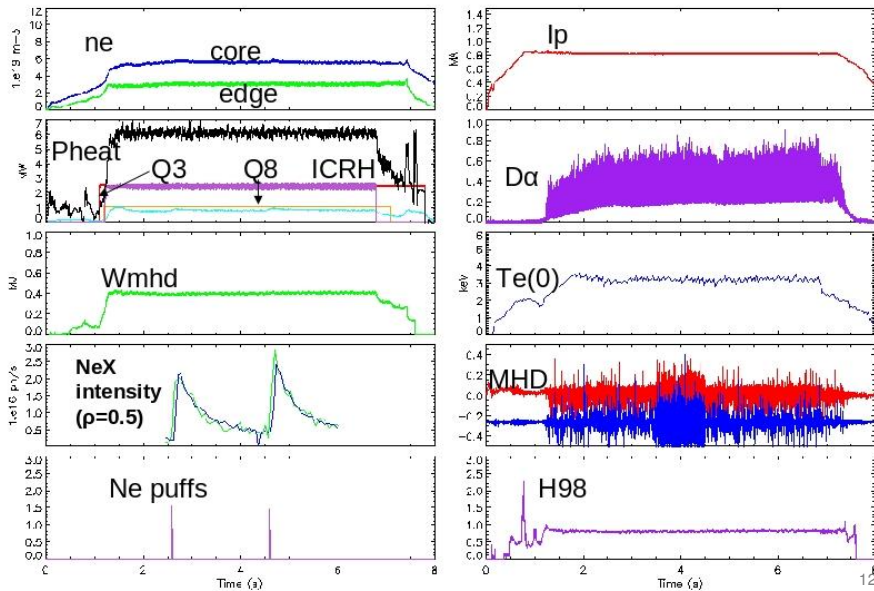


# Outline

- 1 Motivation
- 2 CXRS analysis tools
- 3 CXRS experiments on Boron and Neon**
- 4 Ar experiments

## ASDEX-U shot 19365

#19365





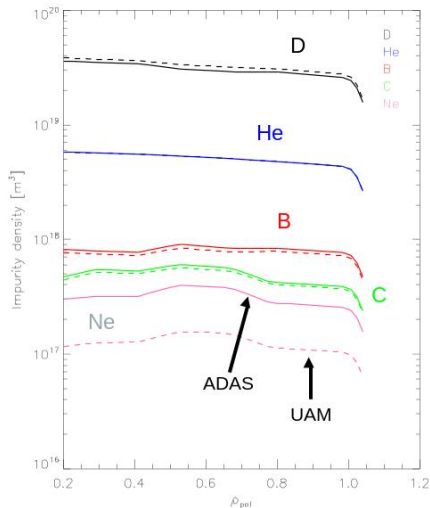
# Measured NeX lines

1	$n=11-10$	$\lambda=524.92$ nm	
2	$n=10-9$	$\lambda =388.37$ nm	Problems of calibration
3	$n=13-11$	$\lambda=388.095$ nm	Too weak
4	$n=14-12$	$\lambda=494.46$ nm	$B^{4+}$ $\lambda=494.47$ nm stronger line
5	$n=15-13$	$\lambda=618.577$ nm	complicated spectra
6	$n=12-11$	$\lambda=690.16$ nm	complicated spectra

## CHEAP impurity densities

Shot #19365

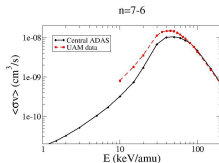
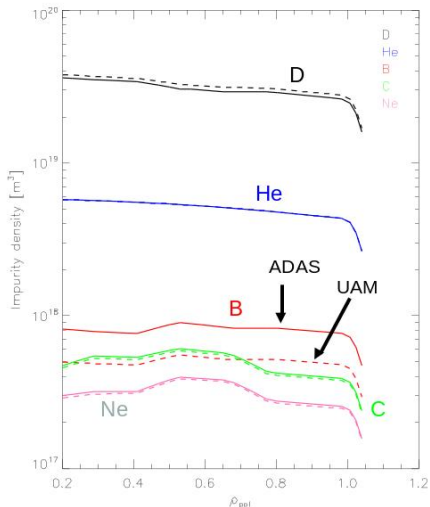
Shot = 19365 Time = 2.750 s



- D: Compensating ion
- He: fix concentration  $n_{\text{He}}/n_e=0.1$
- B: fitted from BV(7-6)  $\lambda=494.47\text{ nm}$
- C: fitted from CVI(8-7)  $\lambda=529.07\text{ nm}$
- Ne: fitted from NeX(11-10)  $\lambda=524.92\text{ nm}$

## Boron checked as well!

Shot = 19365 Time = 2.750 s



- D: Compensating ion
- He: fixed concentration  $n_{He}/n_e = 0.1$
- B: fitted from BV(7-6)  $\lambda = 494.47$  nm
- C: fitted from CVI(8-7)  $\lambda = 529.07$  nm
- Ne: fitted from NeX(11-10)  $\lambda = 524.92$  nm

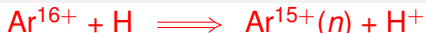
# Outline

- 1 Motivation
- 2 CXRS analysis tools
- 3 CXRS experiments on Boron and Neon
- 4 Ar experiments**



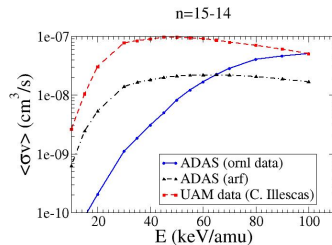
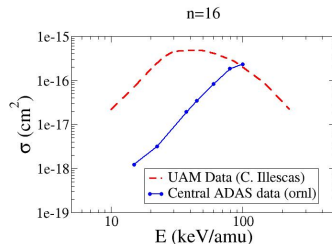
# ADAS sets comparison

$\text{Ar}^{16+} + \text{H}$

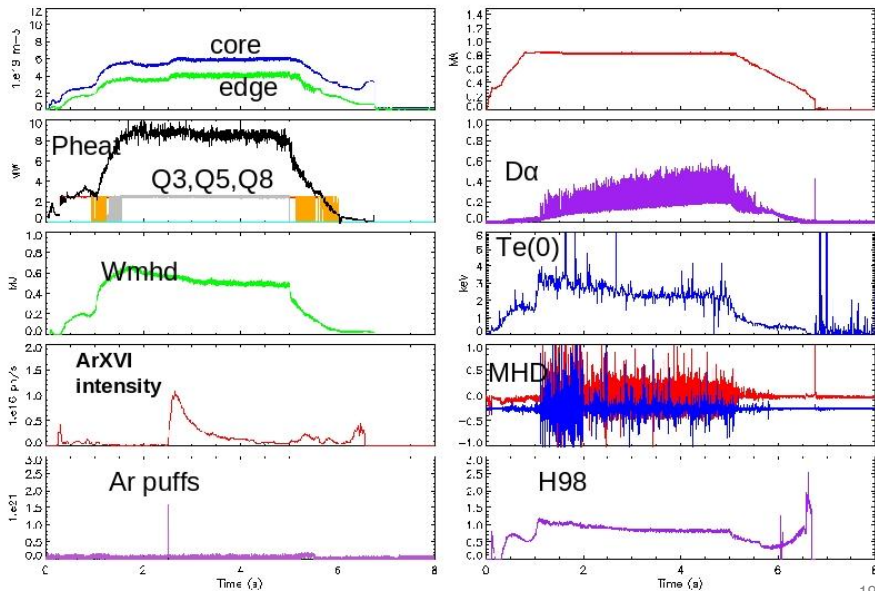


- Factor between 5 and 25 of difference in the  $T_i$  relevant ranges.

- Energy NB  
ASDEX = 30keV  
and 45keV



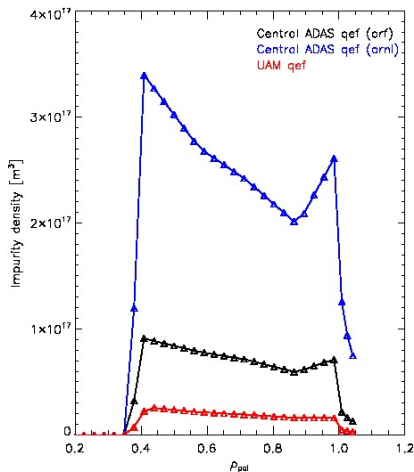
## ASDEX-U shot 22301-22303



# Preliminary comparisons for ArXVI

## Shot 22305; ArXVI profile

Shot = 22305 Time = 2.650 s



Radial density profile obtained from the fitting of calculated line intensity to the experimental one using the CHEAP code in ASDEX-U.  $\rho_{ppl} = 0.5$ ;  $t = 2.65$

Data	ORNL	UAM	ARF	X ray
Conc. Ar	0.02123	0.00104	0.00482	0.001

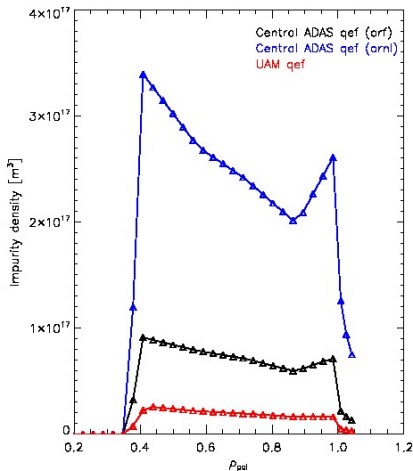
F Guzmán and C. Maggi (Spring 2009).

X ray data provided by M. Sertoli

# Preliminary comparisons for ArXVI

## Shot 22305; ArXVI profile

Shot = 22305 Time = 2.650 s



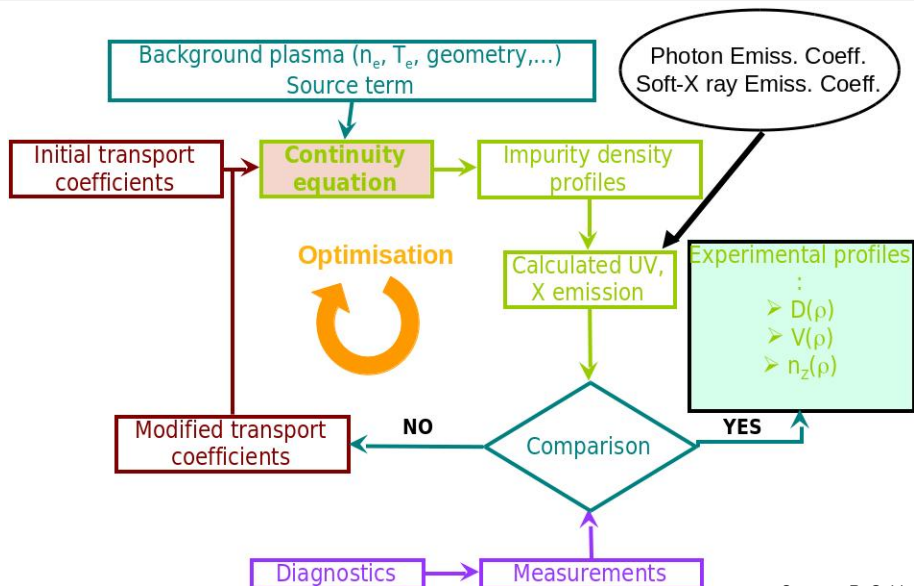
Radial density profile obtained from the fitting of calculated line intensity to the experimental one using the CHEAP code in ASDEX-U.  $\rho_{ppl} = 0.5$ ;  $t = 2.65$

Data	ORNL	UAM	ARF	X ray
Conc. Ar	0.02123	0.00104	0.00482	0.001

UAM data seems to agree with Soft X-ray

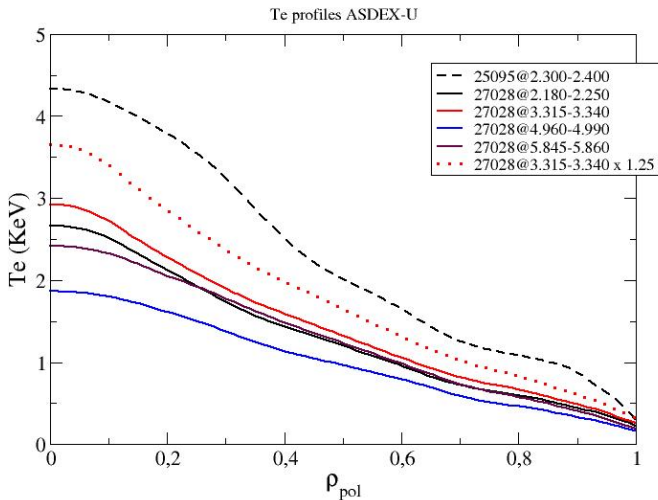
F Guzmán and C. Maggi (Spring 2009).  
 Johann spectrometer data provided by M. Sertoli

## Soft X-ray profiles



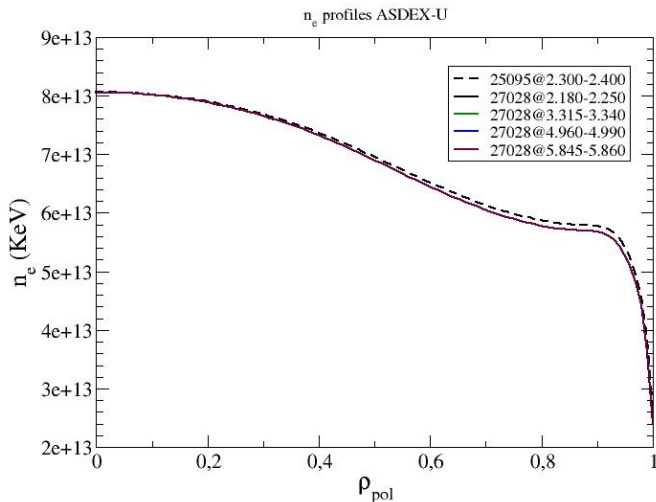
# Ar experiment preparation in ASDEX

## Temperature profiles



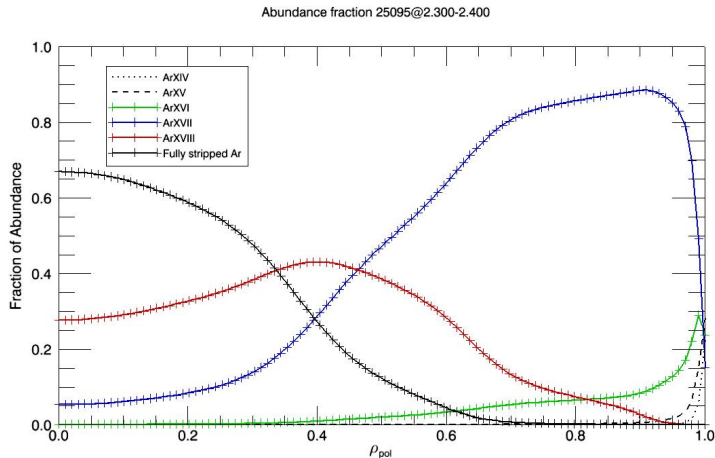
# Ar experiment preparation in ASDEX

## Density profiles



# Ar profiles 25095@2300-2400

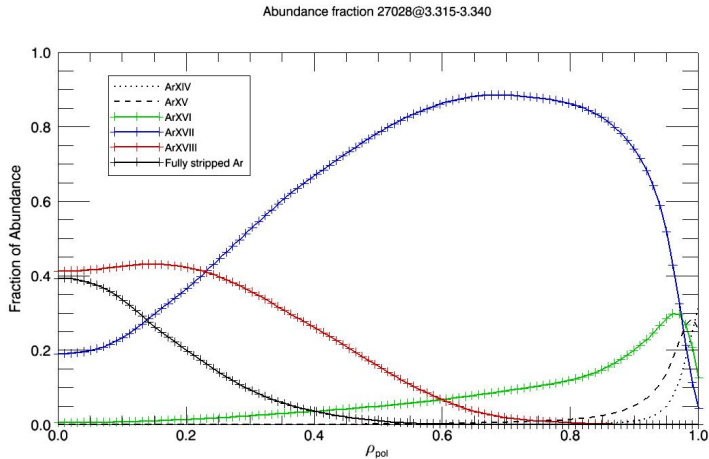
ADAS 405 ion. eq. balance





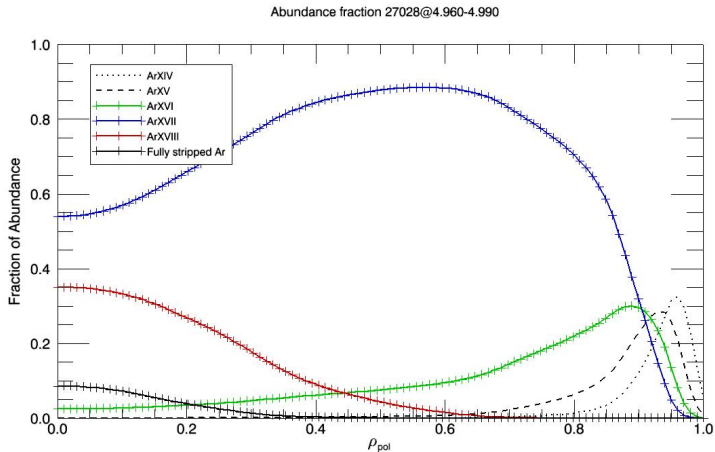
## Ar profiles 25095@3315-3340

ADAS 405 ion. eq. balance



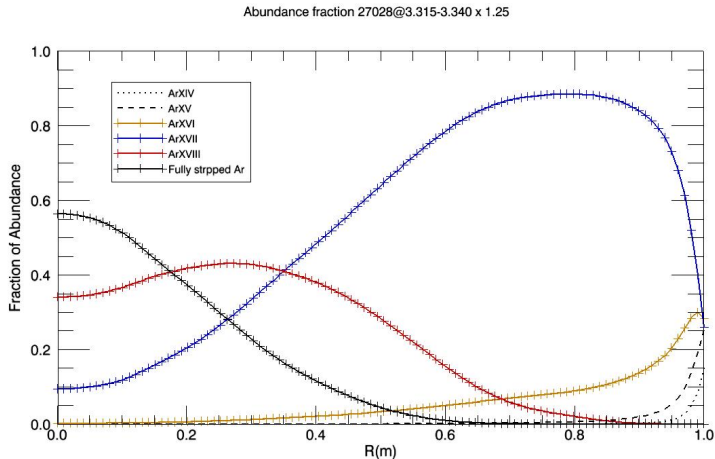
# Ar profiles 25095@4960-4990

ADAS 405 ion. eq. balance



## Ar profiles 25095@3315-3340

ADAS 405 ion. eq. balance



# Summary

- Cross sections accuracy is fundamental to obtain impurities densities by CXRS. There are big differences between the different calculations in cross sections.
- Experimental methods feedback in providing recommended cross sections.
- By comparison of diagnostic profiles two data sets are compared:
  - 1 Electron-impact excitation data with small uncertainties
  - 2 Ion-impact CX data
- Inconsistencies will be detected and the quality of data evaluated.

# Summary

- Cross sections accuracy is fundamental to obtain impurities densities by CXRS. There are big differences between the different calculations in cross sections.
- Experimental methods feedback in providing recommended cross sections.
- By comparison of diagnostic profiles two data sets are compared:
  - 1 Electron-impact excitation data with small uncertainties
  - 2 Ion-impact CX data
- Inconsistencies will be detected and the quality of data evaluated.

# Summary

- Cross sections accuracy is fundamental to obtain impurities densities by CXRS. There are big differences between the different calculations in cross sections.
- Experimental methods feedback in providing recommended cross sections.
- By comparison of diagnostic profiles two data sets are compared:
  - ① Electron-impact excitation data with small uncertainties
  - ② Ion-impact CX data
- Inconsistencies will be detected and the quality of data evaluated.

# Summary

- Cross sections accuracy is fundamental to obtain impurities densities by CXRS. There are big differences between the different calculations in cross sections.
- Experimental methods feedback in providing recommended cross sections.
- By comparison of diagnostic profiles two data sets are compared:
  - ① Electron-impact excitation data with small uncertainties
  - ② Ion-impact CX data
- Inconsistencies will be detected and the quality of data evaluated.